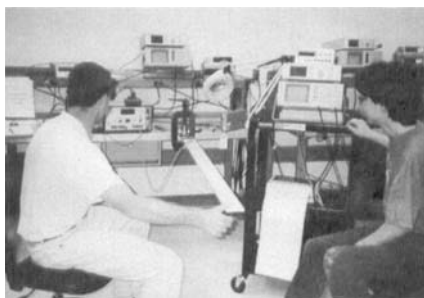


SEM OFFERING AWARD AT 1997 FORMULA SAE COMPETITION

**Formula SAE Competitions will be held
May 15 - 18, 1997**

SEM is offering the "Best Use of Instrumentation in Development" award to Formula SAE competitors. This award will go to the team that has demonstrated the best use of instrumentation in the development of their Formula SAE Vehicle. This includes all forms of transducers, display devices, signal conditioners, data loggers, telemetry systems, and computer equipment (excluding engine management system).

The first place team will receive \$1,000, an award certificate and 15 one-year SEM student memberships. The second place team will win \$500, an award certificate and 10 one-year SEM student memberships. Contact Kristin MacDonald, SEM Managing Director, for additional information, 203-790-6373; Fax 203-790-4472; E-mail kristin@sem1.com.



SEM MEMBER NEWS

Texas Christian University Graduates First Engineering Class

Dr. Patrick Walter, a 20-year SEM member, is the Senior Design Lecturer in TCU's Department of Engineering. The Engineering Department recently graduated its first class. Contact Dr. Walter at e-mail address PWALTER@TCU.EDU for details.

SEM SPRING CONFERENCE UPDATE

**June 2 - 4, 1997
Red Lion Hotel
Bellevue, Washington**

The advance program for the 1997 SEM Spring Conference & Exhibit is now available. Details of the conference can also be found on SEM's web site:

<http://www.sem.bethel.ct.us/>

1997 Conference Highlights:

- 280+ technical paper presentations
- On Wednesday, Murray Lecture presentation by Dr. Rodney J. Clifton of Brown University
- Annual Business Meeting followed by the President's Reception on Sunday, June 1, 1997
- A Tuesday night tour of Blake Island's Tillicum Village, a Native American village, featuring a harbor cruise, salmon dinner and entertainment
- 1997 SEM Spring Conference Exhibits

1997 Spring Conference Exhibitors

APS Dynamics, Inc.
American Stress Technologies, Inc.
BLH Electronics, Inc.

Capacitec, Inc.
The Cooke Corporation
Creative Stars Electro-Optics, Inc.
Fiso Technologies Inc.
Hitec Products, Inc.
Measurements Group, Inc.
Micron Optics, Inc.
Ometron, Inc.
Optim Electronics
PCB Piezotronics, Inc.
Photomechanics, Inc.
Proto Manufacturing Ltd.
Recognition Technology, Inc.
SPIE
Sony Precision Technology America, Inc.
Karl Stetson Associates
Strainoptic Technologies, Inc.
Stress Photonics Inc.
TEC
Texas Measurements

**Add your company's name to the list of
1997 SEM Spring Exhibitors!**

Contact Joni Virgilio:

Phone: 203-790-6373
Fax: 203-790-4472
E-mail: etexpos@sem1.com

Corporate Profile

Editor's Note: SEM is pleased to welcome Photomechanics, Inc. as a new corporate member. So that the readership can be better informed about their products and services, the following company profile is presented. For further information, consult Photomechanics, Inc. directly at the address below.

Photomechanics, Inc.

512 Princeton Drive
Vestal, NY 13850
607-770-7597
607-770-7598 Fax
pemi@photomechanics.com
<http://www.photomechanics.com>

Photomechanics Inc. purchased PEMI (Portable Engineering Moiré Interferometer) and affiliated business from IBM Microelectronics, who designed, developed and marketed PEMI in the past.

Photomechanics Inc. offers innovative product lines dedicated to quantitative

in-situ whole-field displacement and strain measuring capabilities with high sensitivity.

PEMI is suitable even for very small or soft components or structures, such as tiny solder joints and polymer layers in microelectronics. Applications in diverse fields include composite materials, ceramics, fracture and mechanical adhesive joints.

Products are designed primarily for practicing applications engineers without extensive background in interferometry and optical systems. Specialized customer training is available to facilitate productivity.

Photomechanics Inc. products are unique and powerful tools suitable for micromechanical deformation analyses of materials and structures for research, development, education and manufacturing inspection.